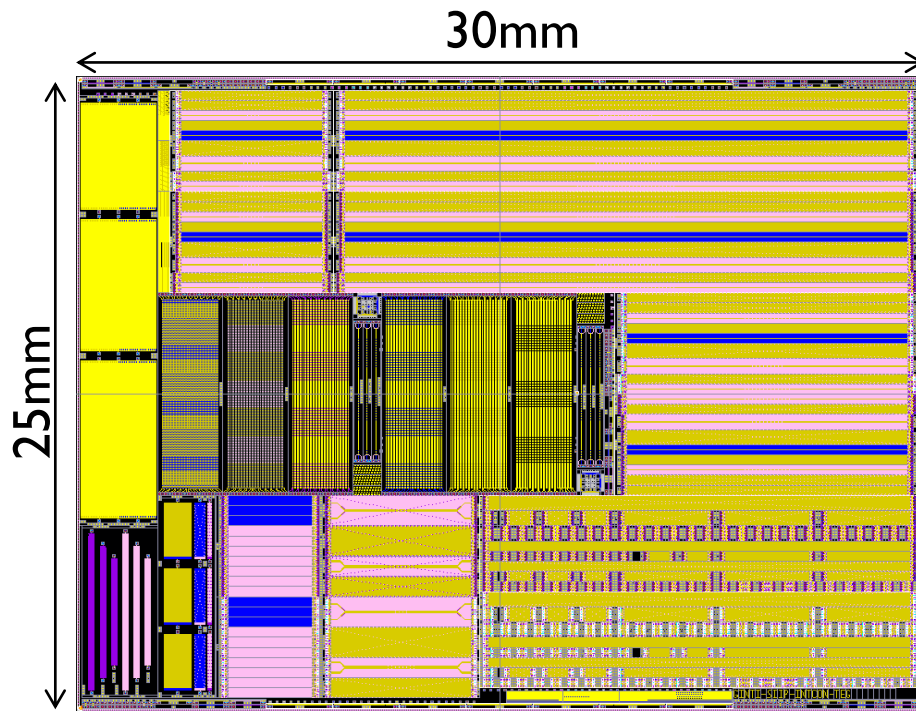
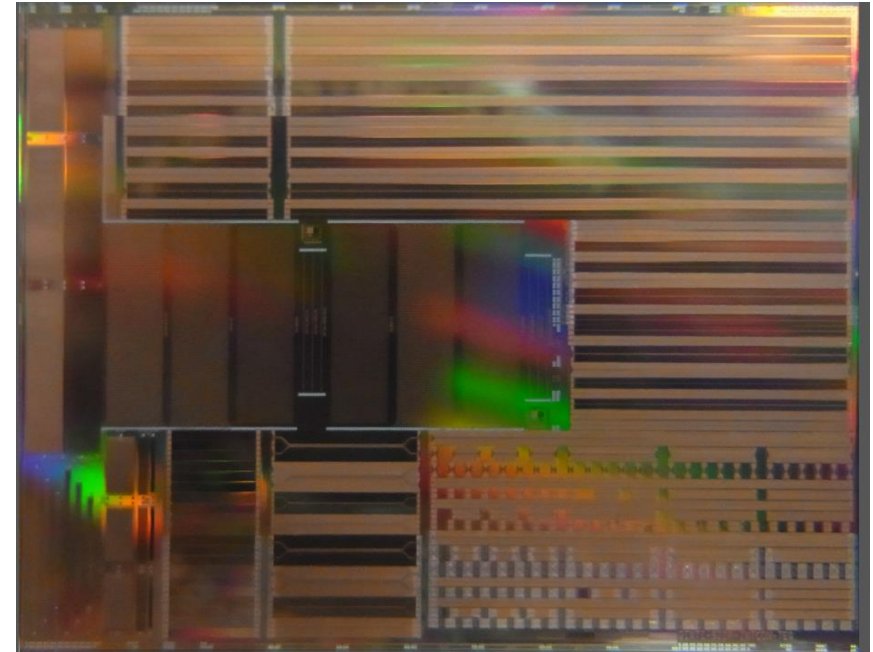





















Si Interposer TEG Chip Layout and Chip Photo



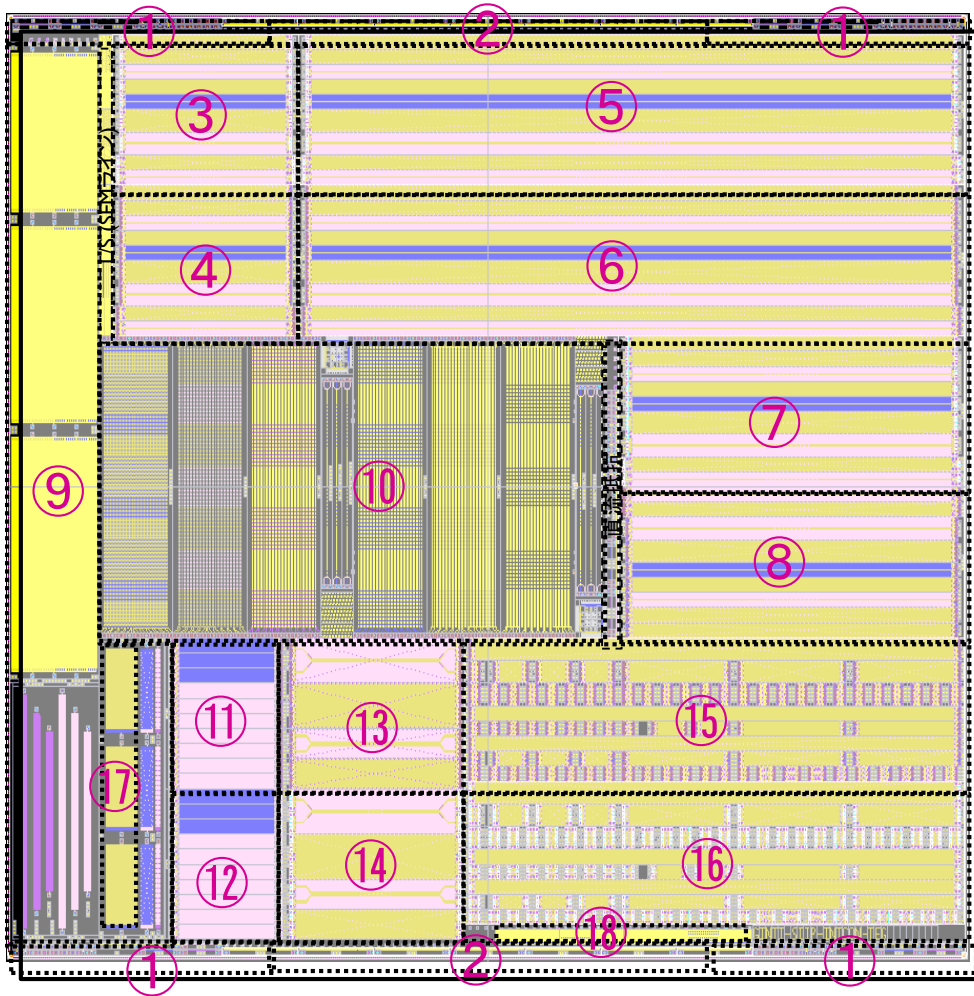
Layout



Chip photo

	IMI		(UBM (F))
	IV1 (via 1)		(Bump (F))
	IM2		TSV
	IV2		BRDL1
	IM3		BPA
	IV3		BRDL1 (Al pad (B))
	IM4		Backside pad open
	IV4		(UBM (B))
	IM5 (Al pad (F))		(Bump (B))
	Pad open		

Evaluation Items in Si Interposer TEG Chip



- ① DC wiring resistance
- ② TSV electromigration
- ③ Transmission line (5mm) (Front pad)
- ④ Transmission line (5mm) (Backside pad)
- ⑤ Transmission line (20mm) (Front pad)
- ⑥ Transmission line (20mm) (Backside pad)
- ⑦ Transmission line (10mm) (Front pad)
- ⑧ Transmission line (10mm) (Backside pad)
- ⑨ Capacitance
- ⑩ Daisy chain
- ⑪ Fine wiring (Backside)
- ⑫ Fine wiring (Front)
- ⑬ Cross talk (Backside pad)
- ⑭ Cross talk (Front pad)
- ⑮ Transmission line pad calibration (Backside pad)
- ⑯ Transmission line pad calibration (Front pad)
- ⑰ SEM pattern
- ⑱ L/S (SEM pattern)